

PATENT NUMBER

U.S. **UTILITY** Patent Application

<p>ID</p> <p>O.I.P.E.</p> <p>SCANNED <u>AC 2</u> Q.A. <u>LA</u></p>	<p>PATENT DATE</p>
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APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER Dugan Boady ✓
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APPLICANTS

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3.1.1.1

Memory LSI failure analysis apparatus and analysis method thereof

PTO-2040
12/89

ISSUING CLASSIFICATION												
ORIGINAL				CROSS REFERENCE(S)								
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
INTERNATIONAL CLASSIFICATION												

Continued on Issue Slip Inside File Jacket

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
The term of this patent subsequent to _____ (date) has been disclaimed.				NOTICE OF ALLOWANCE MAILED	
	(Assistant Examiner)		(Date)		
The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____ _____				ISSUE FEE	
				Amount Due	Date Paid
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The terminal ____ months of this patent have been disclaimed.				ISSUE BATCH NUMBER	
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